ISO 24173:2024-02 (E)

Microbeam analysis - Guidelines for orientation measurement using electron backscatter diffraction

Contents

Page

Foreword iv

Introduction v

1 Scope 1

2 Normative references 1

3 Termsanddefinitions 1

4 Equipment for EBSD 6

5 Operating conditions 7
5.1 Specimen preparation 7
5.2 Specimen alignment 7
5.3 Common steps in collecting an EBSP 7
5.3.1 Setting the microscope operating conditions 7
5.3.2 Detector and working distances 8
5.3.3 Camera integration/exposure time 8
5.3.4 Binning 8
5.3.5 EBSP averaging 9
5.3.6 EBSP background correction/EBSP signal correction 9
5.3.7 Band detection 10

6 Calibrations required for indexing of EBSPs 11

7 Analytical procedure 14
7.1 Operating conditions 14
7.2 Equipment stability check 15
7.3 EBSD analysis 15

8 Measurement uncertainty 15
8.1 General 15
8.2 Uncertainty of crystal orientation measurement 15
8.3 Absolute orientation 15
8.4 Relative orientation 15

9 Reporting the results 16

Annex A (informative) Principle of EBSD 17

Annex B (informative) Specimen preparation for EBSD 18

Annex C (informative) Brief introduction to crystallography and EBSP indexing, and other information useful for EBSD 24

Bibliography 39